

Nikon offers total software solution covering image capture, archiving, and analysis

NIS-Elements is an integrated software imaging platform developed by Nikon which delivers comprehensive microscope control, image capture, documentation, image analysis and data management. NIS-Elements handles multidimensional imaging tasks flawlessly with support for capture, display, peripheral device control, and analysis & data management of images of up to six dimensions. The system also contributes to experiment efficiency with an intuitive image analysis feature set and database building capabilities developed to handle archiving and management of large numbers of multidimensional image files.

Unified control of the entire imaging system offers significant benefits to microscopists for cutting-edge research, such as live cell imaging

> The NIS-Elements suite is available in three packages scaled to address specific application requirements.



NIS-Elements AR is optimized for advanced research applications, featuring fully automated acquisition and device control through full 6D (X, Y, Z, Lambda (Wavelength), Time, Multipoint) image acquisition and a wide range of image analysis.



NIS-Elements BR is suited for standard research applications, photodocumentation of fluorescent samples and image analysis including intensity and counting measurements. It features acquisition and device control through 4D (up to four dimensions can be selected from X. Y, Z, Lambda (Wavelength), Time, Multipoint) acquisition.



NIS-Elements D supports color documentation requirements in bioresearch, clinical and industrial applications, with basic measuring and reporting capabilities.

Why NIS-Elements?

As a leading microscope manufacturer, Nikon realizes the importance of providing its customers with system-based solutions to free them to focus on their projects and research and not on the complexities of the microscope. Never before has a software package offered such comprehensive control of microscope systems, image acquisition, image analysis and data management.



Highest Quality Optical Performance

Total Imaging Solution

The world-renowned Nikon CFI60 infinity optical system effectively set a new standard for optical quality by providing longer working distances, higher numerical apertures, and the widest magnification range and documentation field sizes.

As a leader in digital imaging technology, Nikon recognized the importance of adapting its optics to optimize the digital image. Nikon's new objectives and accessories are specifically engineered for digital imaging.

Because what you see depends greatly on the quality of your microscope, we strive to power our microscope systems with optical technologies that are nothing but state-of-the-art.

•Diverse Line of Powerful Digital Cameras

Image capture has become a high priority in microscopy and the demand for products that deliver high quality and versatile functionality has grown considerably in recent years. In accordance, Nikon offers a full line of digital cameras, addressing the varied needs of microscopists in multiple disciplines. Each Nikon digital camera is designed to work seamlessly with Nikon microscopes, peripherals, and software. With Nikon Digital Sight (DS) series cameras, even novice users can take beautiful and accurate microscopic images. For the advanced researcher, hiresolution image capture and versatile camera control is fast and simple. Together with Nikon's new software solutions, image processing and analysis have reached new levels of ease-of-use and sophistication.

Intelligent Software Solutions

Designed to serve the needs of advanced bioresearch, clinical, industrial and documentation professionals, NIS-Elements provides a totally integrated solution for users of Nikon and other manufacturers' accessories by delivering automated intelligence to microscopes, cameras, and peripheral components. The software optimizes the imaging process and workflow and provides the critical element of information management for system based microscopy.

Multi-layer Document Structure

NIS-Elements uses a sophisticated image documentation structure making it possible to achieve non-destructive archiving of image data including annotation (arrows, lines, text notes), measurement data, binary data for storing results of threshold or classification processes, and meta-data information for recording acquisition and device conditions at the time of image acquisition.

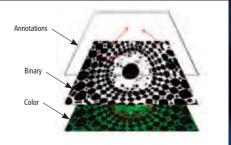


Image Acquisition

NIS-Elements offers the most suitable image acquisition for various applications with the integrated control of the camera, motorized microscope and peripheral devices.

Multichannel (multi color)

Z-series

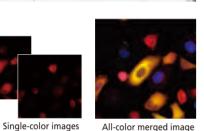


Ar Br D

Ar Br D

NIS-Elements can acquire full bit depth multi-color images, combining multiple fluorescence wavelengths and different illumination methods (DIC, phase contrast etc.), while offering independently scalable channels.



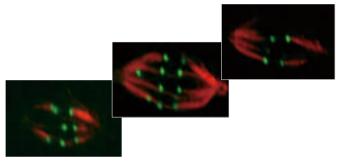


All-color merged image

Specified-color merged image

Through motorized focus control, NIS-Elements reconstructs and renders 3D images from multiple Z-axis planes.

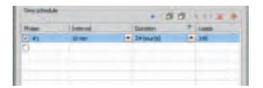


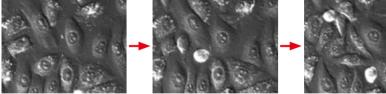


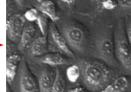
Time Lapse

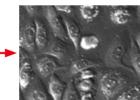
Time lapse imaging in NIS-Elements is easily configurable simply by setting the time interval and duration of capture.

The Perfect Focus System of the motorized inverted microscope Ti-E enables high-accuracy image capture without focus drifting even during extended time time-lapse experiments.



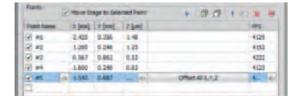






Multipoint Experiments

NIS-Elements' motorized stage control offers automated travel to multiple stage points of the sample of a multi-well plate or dish. Stage points are memorized and can be saved and loaded for future imaging sessions.



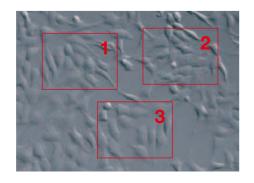
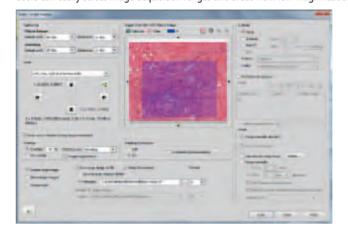


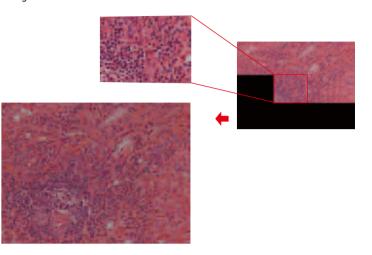
Image Stitching (Large image) New





Large Image Acquisition generates a single high-magnification wide field-of-view image by automatically stitching multiple adjacent frames from a multipoint acquisition using a motorized stage or from multiple single images captured from a previous session. Users can easily select image acquisition ranges and areas from low magnification images.





Multidimensional imaging

ND Acquisition

NIS-Elements captures images in a combination of multiple dimensions such as Time-Lapse, Multichannel, Z-series, and Multipoint. It is also possible to create and manage the acquisition of a multi-dimensional dataset with a thirty-minute time lapse of two wavelengths and a Z series across each well of a multiwell plate.



Option (Ar)

* Available dimensions vary depending on the package.

ND Stimulation

Option (A)

NIS-Elements controls photo stimulation and image acquisition.



ND Simultaneous Stimulation

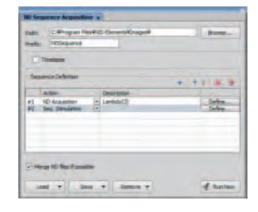
NIS-Elements enables image acquisition during photo stimulation.



ND Sequential Acquisition

NIS-Elements allows various sequential imaging experiments to be combined with other functions, such as simultaneous photo stimulation and imaging, or multidimensional acquisition.

Option (A)

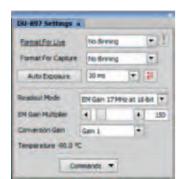


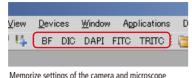


Optical Configuration

Ar Br D

Presets or 'Optical Configurations' can be saved for each observation method such as FITC fluorescence and DIC imaging, memorizing the settings of the microscope, camera and peripheral devices. The optical configurations are created through a one click set up and are displayed as icons in the tool bar for easy access and use.







Movie Capture, Fast Image Capture

NIS-Elements has several options to observe and capture a sample's change and fast movement.

Fast Time Lapse

Fast Time Lapse is designed for ultra high-speed cameras. The hard disk drive can be used together with PC memory to enable a longer acquisition time.



RAM Capture

RAM Capture allows for acquisition at the fastest possible rate of the camera. A RAM buffer is utilized to enable capture and retrieve a high speed time lapse, which aids in the capture of fleeting events such as calcium sparks, motility and translocation.



AVI Live-Stream Capture

AVI Acquisition automatically captures live data into an easily exportable and viewable AVI format.



Time Saving Acquisition by Hardware Collaboration

Nikon's original technology optimizes image acquisition speeds by synchronizing the camera with the microscope and peripheral devices.

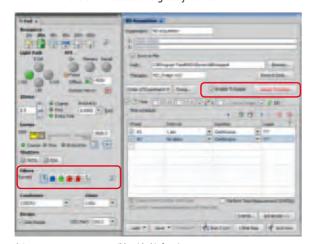
Trigger Acquisition

Triggering external devices directly from the camera enables synchronized control of various devices such as the laser unit without passing through the PC. This allows for the fastest performance of the system components for multi-wavelength excitation in TIRF observation.



Ti-recipe

This function enables the HUB-A controller of the motorized inverted microscope Ti-E to control both image acquisition and change of fluorescent filter, motorized stage and fluorescent shutter by directly connecting the camera and a HUB-A controller without passing through a PC. As a result of optimizing the communication times of all connected devices, acquisition times for multi-dimensional datasets are greatly reduced.



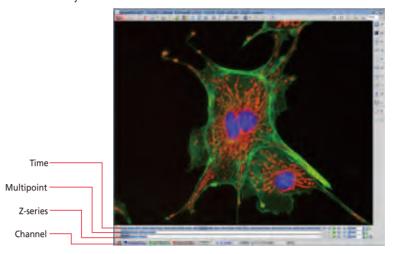
^{*} Some cameras are not compatible with this function. For more information, please contact Nikon or its authorized representative.

Display and Data Processing

Various methods are available for displaying and processing captured images and datasets.

Multi-dimensional Image Display

NIS-Elements displays time lapse, multi-channel, multiple X, Y, Z positions in an intuitive layout, which allows for automatic playback and the ability to select subsections of the data to be saved as a new file.





Merge Channels

Multiple single channel images (ex., two from three-channel acquisition images) can be merged together to create an overlay of full depth separately scalable images. With AR and BR, images can be merged by simply dragging the tab of one image onto another image. With D, images are merged by selecting each image for red, blue, green and brightfield channels



Ar Br D



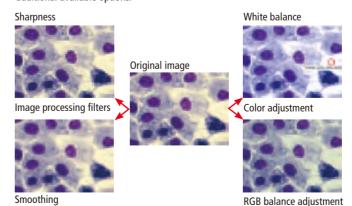
Ar Br D

Image Processing

Image Filtering, Color Adjustment

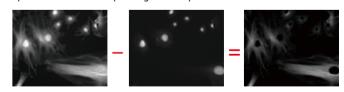
*Usable functions vary depending on the package.

With NIS-Elements image processing tools, it is possible to modify image display and feature extraction using various filters for, for example, sharpness, smoothing and detection. White balance and RGB/HIS balance adjustment are additional available options.



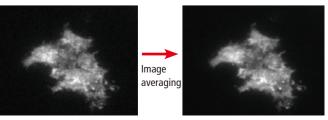
Ar Br Option (D) **Arithmetic operation (Image arithmetic)**

NIS-Elements enables arithmetic operations such as addition, subtraction, multiplication and division on an image or between multiple images. Arithmetic operation between multiple images is also possible.



Arithmetic operation (Image averaging)

NIS-Elements reduces the noise of an image by averaging multiple sequential images such as time-lapse images. Rolling averaging that does not reduce frame rate is available as well.



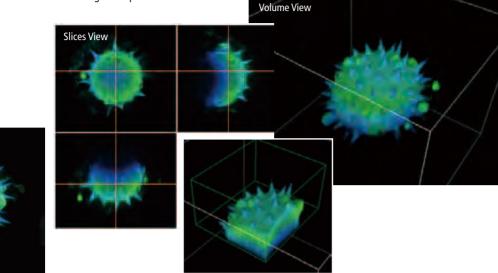
Ar Br D

Z-Series Image Display

Projection

* Volume view and slice view are only possible with AR and BR. Ar Br D

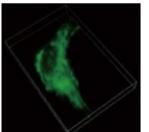
Z-series images can be displayed in various formats such as max. and min. projections, X-Z axis and Y-Z axis cross-sectional slice view and 3D volume view. Rotatable 3D volume rendered views from 3D datasets are easily converted to an AVI or MOV format for file sharing and export.



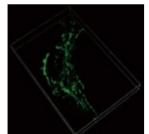
Deconvolution Option (Ar)

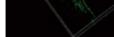
3D Deconvolution

Haze and blur of the acquired fluorescence image can be eliminated. By reassigning out-of-focus intensities back to the spatial locations to where they originated, the intensity of the image is kept and allows for quantitative analysis. Algorithms for wide-field fluorescence, point-scanning confocal and spinning-disk confocal images are available.



Before deconvolution

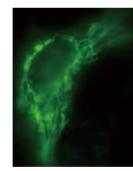


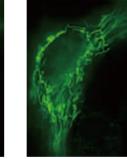


After deconvolution

2D Deconvolution

The 2D deconvolution module can be applied to a live image or an already acquired dataset. The module also allows the elimination of out-of-focus blur from live images and multidimensional images.





Before deconvolution

After deconvolution

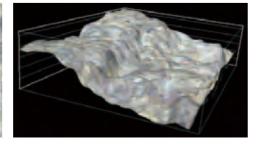
Extended Depth of Focus (EDF)

Option (Ar Br D)

NIS-Elements EDF function selects the in-focus area from multiple Z-stack images, and produces one all-in-focus image. The composite image can be viewed and rotated as a virtual 3D image, as it contains Z-axis information.



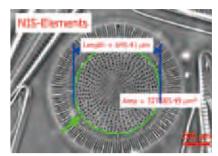




Measurement and Analysis

Manual Measurement (Interactive Measurement) and Image Annotation

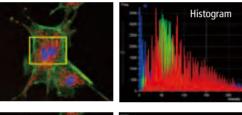
Interactive Measurement allows easy measurement of length and area by drawing lines or an object directly on the image. The results can be attached to the image, and also exported as text or to an Excel spreadsheet. Annotations such as arrows, circles, squares, text are also available display options.

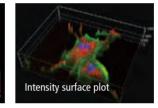




Histogram/Intensity Line Profile/Intensity Surface Plot 💹 📴 🖸

Histogram measurement measures the intensity distribution of pixels across the whole image or a defined region. An intensity line profile measurement shows the intensity distribution on a defined line. The Intensity Surface plot shows the intensity distribution of an image with the height of the z-axis line.





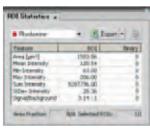


ROI Statistics

*Usable functions vary depending on the package. Common pixel measurements such as area, maximum or minimum intensity are possible with the user defined ROI (Region Of Interest).

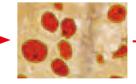
ROI or multiple ROIs statistic results for a single image or a multi-dimensional dataset are displayed and easily exported as text or an excel

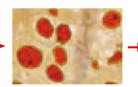




Auto measurement measures the number or area of objects which are extracted from images by the creation of a binary layer through thresholding using RGB/HIS or intensity values. The results can be listed or exported as text or an excel file. It is possible to save and reuse thresholding parameters.



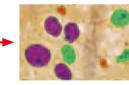




Classifier

Object Classifier

Object classifier uses objects identified by thresholding along with additional features such as shape factors, and other statistical methods including nearest neighbor and neural networks for



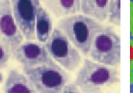
classifying objects into multiple categories. It is also possible to teach the module based on interactive 'picking' of image pixels.

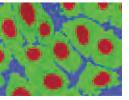
Ar Br Option (D)

Option (Ar

Pixel Classifier

This function classifies each pixel in the image with RGB/HIS and intensity across the whole image. Results are reported in percentage and it possible to save and reuse parameters across a large sample of images. Multiple binary layers are also displayed with multiple colors on the image and are available with other analysis tools within the software package.





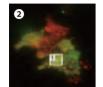


Time (Intensity) Measurement

Ar Option (Br)

Time measurement creates a graph of seguential intensity changes while time-lapse imaging or from captured time-lapse images. Ratio view function* allows the measurement of the ratio of two wavelengths across multiple ROIs and shows the ratio value by pixel. Numeric data and graph images are exportable and the measurements on the graph are available as well. (* Only with AR)



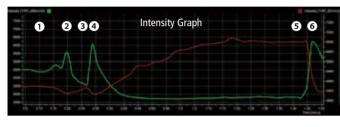


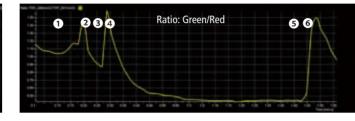








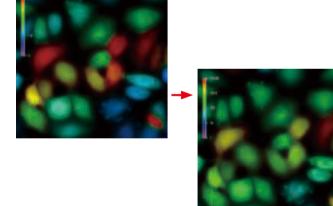


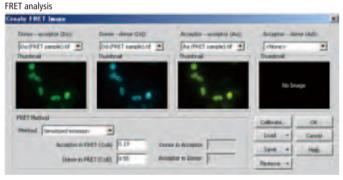


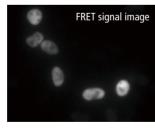
Calcium & FRET Option (Ar)

Ca2+ ion concentration calibration of the ratiometric fluorochrome Fura2, for example, is available using an easily configurable wizard. Corrected FRET image and FRET efficiency, reported in percentage is also available using three filter sets (three types of excitation-fluorescent combination: "Donor – Donor," "Acceptor" and "Donor – Acceptor") and two bleed-through factors.

Ca2+ ion concentration calibration from ratiometric value





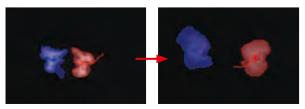




Object Tracking

Option (Ar)

2D tracking of an object utilizes the threshold of objects over time and produces measurements such as velocity, acceleration, and distance from a specified origin. The tracking module offers both automated tracking and manual tracking methods.





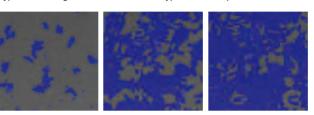
Cell Proliferation/ Wound Healing/ Cell Count/ Cell Motility New

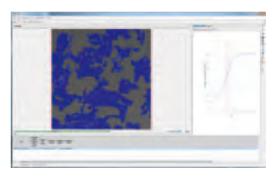


Enables quantitative live-cell analysis utilizing non-invasive label-free phase contrast images, which reduces damage to live cells and allows for long term time-lapse imaging. By simply selecting the desired magnification and pre-programmed "recipe", which is optimized for various cell types, cell detection and analysis are automatically started.

CQ Cell Proliferation

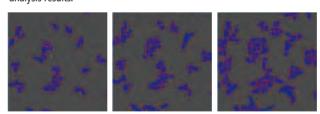
The software automatically detects areas covered by cells, allowing for the quantification of cell proliferation and the generation of growth curves even in high-density areas. Label-free phase contrast imaging enables long-term, noninvasive monitoring of cells and is thus an optimal method for evaluating growth conditions and characteristics. Stable analysis results are secured regardless of cell type, eliminating the need to select cell type from a recipe.

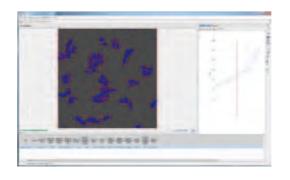




CO Cell Count

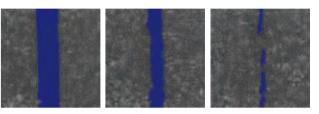
The software automatically detects and quantifies the number of cells and the size of individual cells. Phase contrast imaging enables low-invasive analysis because cell staining is not required. Cell detection and analysis is carried out by selecting the appropriate cell type and magnification from the "recipe" menu. Detection accuracy can be further improved by customizing a recipe allowing for robust analysis results.

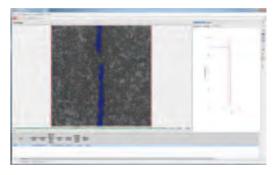




CQ Wound Healing

The software automatically detects and measures the wound area during invitro wound healing experiments. It can be used to quantitatively analyze the effects of drug treatment on cellular activities such as motility and growth in a wide range of applications, including cancer research, drug development, and stem cell research. Stable analysis results are secured regardless of the cell type, eliminating the need to select cell type from a recipe.

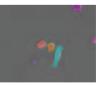


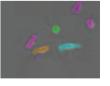


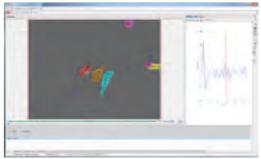
CO Cell Motility

The software automatically detects cell centroids and continuously tracks their movements, generating quantitative results including XY positions of cells, their velocities, lengths of trajectory and persistence. This software module can be used to evaluate cell motility under various conditions such as drug treatment. Users can further optimize detection and analysis parameters for their cells of interest by customizing the recipe.







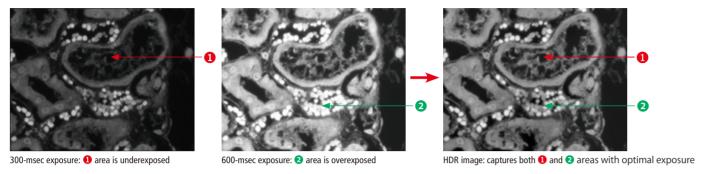


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Others

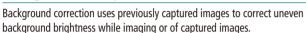
HDR (High Dynamic Range) Image Acquisition

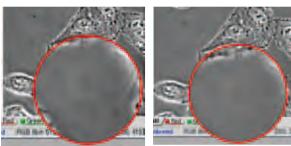
HDR creates an image with appropriate brightness in both the dark and bright regions in a sample by combining multiple images acquired with different exposure settings. It is also possible to create HDR image using multiple captured images.



Ar Br D

Background Compensation



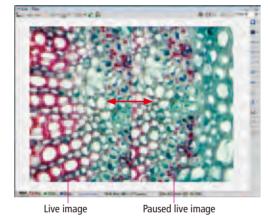


Before compensation After compensation

Live Image Comparison



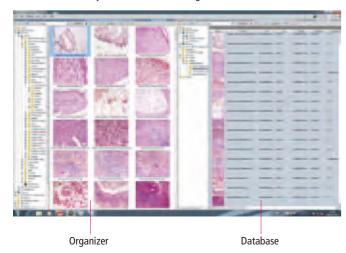
Live Compare enables easy image comparison between a sample image and a live image. Live observation side by side with a paused live image is also available in split screen mode.



Database

Option (Ar Br D)

Using the organizer function, captured images are displayed in thumbnails for easy retrieval of the desired image. By simply clicking on the thumbnail image in this view, the image is easily opened. Sorting and filtering this database of images and datasets using acquisition details such as objective settings, date and author is an easy method for data management as well.



Report Generation

Images captured with NIS-Elements have information such as acquisition details and analysis results, allowing export and PDF conversion of the image and the associated image header and data information.



Ar Br D

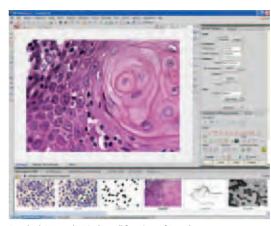
User Control

For safe system management, it is possible to individually limit each user authorization using the user account of Windows® (such as the Administrator or Guest). It limits the authorization and modification of the settings of devices (microscopes or other), optical configuration and layout editing.

GUI Option

Industrial Simple GUI

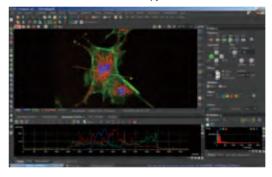
With D package, the simple GUI mode provides controls for the most common operations such as image capture and simple measurement.

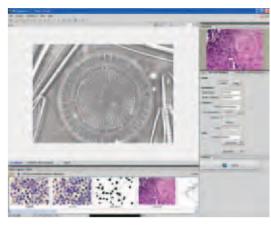


Standard GUI mode: Displays all functions of D package

Dark Color Scheme

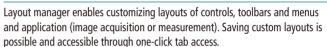
This popular display option mode has a brightness level interface color palette suitable for use in a dark microscopy room.



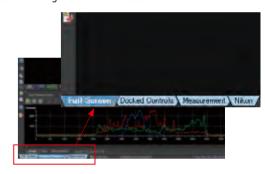


Simple GUI mode: Display only image capturing and measurement

Layout Manager



Advanced Solutions for your Imaging World NIS Elements



Compatibility with Third-party Products

NIS-Elements is compatible not only with Nikon products but also with third-party products such as high-sensitivity CCD cameras and peripheral devices. Third party devices and cameras are easy to integrate through the NIS-Elements intuitive install and device manager.

Off-line Package for Analysis

The NIS-Elements off-line software package offers analysis tools such as intensity measurements and object counting of tiff and multi-dimensional format images captured with Nikon's microscopes and third-party software.

Viewer Software

This is free software for image display of single images and datasets captured using NIS-Elements. Possible views include Tile View, Max/Min Projections and 3D Volume View. Saving multi-dimensional files into TIFF format is available as well. The viewer is downloadable from the Nikon website.

Software Upgrade Agreement (SUA) License

NIS-Elements can be upgraded for one year from the date of purchase. The Software Upgrade Agreement (SUA) License, which is purchasable in one-year license segments, extends the access to the latest version of NIS-Elements.













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Supporting Broad Microscope Imaging

NIS-Elements is a common software platform for Nikon microscope systems, which allows the comprehensive control of wide range of functions for cameras, confocal imaging systems and super resolution microscopes.

NIS-Elements C

NIS-Elements C is an optimized software package for confocal imaging. It is compatible with highspeed/high-resolution confocal microscope A1+/A1R+, multiphoton confocal microscope A1 MP+/ A1R MP+, confocal microscope C2+ and spectral confocal imaging systems.

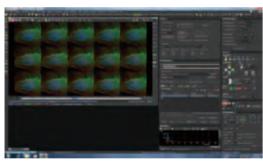




N-SIM Analysis option

N-SIM Analysis option allows control of Nikon Super-Resolution Microscope N-SIM, which can achieve an image resolution of 85nm and temporal resolution of up to 0.6 sec/frame using high frequency

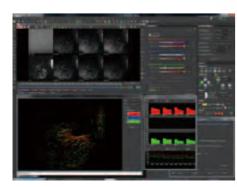
Structured Illumination.





N-STORM Analysis option

N-STORM Analysis option enables control of Nikon Super-Resolution Microscope N-STORM, which realizes an incredible image resolution of approx. 20nm by utilizing STochastic Optical Reconstruction Microscopy (STORM).





Enatures

	AR	BR	D
Window style	MDI (Multiple	MDI (Multiple	SDI (Single
	Interface)	Interface)	Interface)
	Dark color scheme	0	0
Industrial simple GUI	_	_	0
Camera control	0	0	0
Microscope control	0	0	0
Nikon made peripheral control	0	0	0
Non-Nikon peripheral control	0	0	0
Live image capture	0	0	0
Time-lapse image capturing (T)	0	0	Δ
Z-series image capturing (Z)	0	0	0
Multichannel image capturing (λ)	0	0	
Multipoint image capturing (MP)	0	0	0
Multidimensional image capturing	Up to 6D	Up to 4D	0
	• Op to 6D	● 0p to 4D	
Stimulation experiment			
RAM capture	0		
HDR image capture	0		
AVI live-stream capture	0	0	0
Objective calibration	0	0	0
Capturing data savings (Meta-data)	0	0	0
Image filtering	0		
Binary	0	Δ	<u> </u>
LUT (look up table)	0	0	0
Histogram	0	0	0
Manual measurement	0	0	0
Auto measurement	0	0	•
Intensity line profile	0	0	0
Intensity surface plot	0	0	0
Time (intensity) measurement	0	•	_
3D measurement	•	A	A
Volume measurement	0	_	_
Database	•	•	•
Macro	0	Δ	Δ
Advanced interpreter	0	•	•
Report generator	0	0	0
Live compare	0	•	•
Volume view	0	Δ	Δ
EDF (Extended depth of focus)	•	•	•
3D surface view	•	•	•
Ratio view	0	_	_
SD deconvolution	•	_	_
AQ blind deconvolution	•	_	_
2D real time deconvolution	•	_	_
2D deconvolution	•	_	_
3D deconvolution	<u> </u>		
2D/3D deconvolution	•		
3D blind deconvolution	•		
Wavelength switcher	•	•	•
TTL/analog IO	•	•	•
Object classifier	•		
•	•		
Object tracking	•	_	
Calcium & FRET			_
CQ Cell Proliferation	•	_	
CQ Wound Healing	•		
CQ Cell Count	•	_	_
CQ Cell Motility	•		
N-SIM analysis	•		
N-SIM offline analysis	•		
N-STORM analysis	•	_	_
N-STORM offline analysis*	•		
Metalogical analysis	_	_	

 $[\]bigcirc$: Full function \triangle : Limited function —: Not available \bigcirc / \triangle : Option

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^{*} N-STORM analysis is required.

NIS-Elements Supported Devices (ver. 3.22 or later)

Nikon Cameras CCU: DS-U1/L1*2 (for camera head DS-2Mv/2MBW/2MBWc/5M/5Mc) CCU: DS-U2/L2 (for camera head DS-2Mv/Vi1/2MBW/2MBWc/5M/5Mc/Fi1/Fi1c/Qi1/Ri1) CCU: DS-U3/L3*3(for camera head DS-Vi1/Fi1/Fi1c/Qi1/Ri1/Fi2) DOC-FS Third-party Cameras Photometrics Fvolve QuantEM CoolSNAP HO2 CoolSNAP ES² Cascade 128+*2 Cascade II 512*2 Cascade 1K^{*2} Andor Technology Luca S, Luca R iXon+ 897, 888, 885 iXon X3 iXon Ultra iKon-M Clara Neo sCMOS Qlmaging Retiga EXi Aqua/Blue Retiga 2000R - Mono/Color Retiga SRV + RGB-HM-S Slide Rolera EMC2 OICLick QICAM Hamamatsu magEM C9100-13 ImagEM-1K ORCA-R2 ORCA-Flash 2.8 ORCA-Flash 4.0 ORCA-D2 ORCA (DCAM)

*1 Only compatible with Windows XP
*2 Not compatible with 64 bit version OS
*3 Not compatible with Windows Vista

Monitor images are simulated.

C9100-02, C9100-12

Imaging Source Converter DFG/1394

Others TWAIN Device*

Nikon Microscope Devices
Biological Microscope TE2000 (Perfect Focus System), Ti (HUB-A/B) Biological Microscope 90i (ND fiter, Stage), 80i, DIH-E/M, C-Box, Biological Microscopes Ni-E/Ni-U, Ci-E

Fixed-stage Microscope FN1 + DIH Multizoom Microscope AZ100M Industrial Microscope LV Series Measuring Microscope MM-400/800°2 Metallographic Microscope MA200 Inspection Microscopes L200N/L300N Fiber Illuminator Intensilight

Laser Module LU4A, Shutter Unit LUSU, AOM Unit

LV NCNT Nosepiece controller

D-FI-F LUSU $\Delta \Omega M$ LU4A Ni-SH-CON

Third-party Devices

Prior Scientific ProScan III (H31) ProScan II (H30) Prior PCI II OptiScan II ES10 NZ100, nanoStageZ Prior ES10ZE Prior NIKRFK **Ludl Electronic Products**

MAC5000, MAC6000 Märzhäuser Wetzlar TANGO Desktop, Tango PCI LSTEP, ECO-STEP Vincent Associates (Uniblitz) VCM-D1

Lambda 10-2, 10-3, SC, 10-B, XL Physical Instrument PI E-662, 665 (RS232) **Photometrics Dual View EXFO** EXFO XCite120

Sutter Instrument

ASI (Applied Scientific Instrumentation)

MS-2000 FW-1000 SC-2000 National Instruments

TTL Input/Output (NI Card)

Supported Operation System

Windows 7 Professional (32/64 bit Version) Windows Vista Business SP2 (32/64 bit up to Version 3.22) Windows XP Professional SP3 (32 bit up to Version 3.22)

NIS-Elements is compatible with all common file formats, such as JP2, JPG, TIFF, BMP, GIF, PNG, ND2, JFF, JTF, AVI, ICS/IDS. ND2 is a special format for NIS-Elements. ND2 allows storing sequences of images acquired during nD experiments. It contains information about the hardware settings and the experiment conditions and settings.

WARNING

TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING YOUR EQUIPMENT.







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